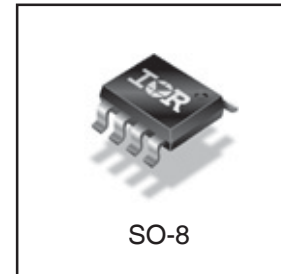
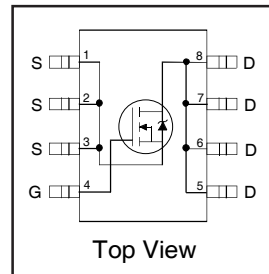


HEXFET® Power MOSFET

$V_{DS}$	80	V
$R_{DS(on) \max}$ (@ $V_{GS} = 10V$ )	15	m $\Omega$
$Q_g$ (typical)	35	nC
$I_D$ (@ $T_A = 25^\circ C$ )	9.3	A



**Features**

Industry-standard pinout SO-8 Package
Compatible with Existing Surface Mount Techniques
RoHS Compliant, Halogen-Free
MSL1, Industrial qualification



**Benefits**

Multi-Vendor Compatibility
Easier Manufacturing
Environmentally Friendlier
Increased Reliability

Base Part Number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRF7493PbF-1	SO-8	Tube/Bulk	95	IRF7493PbF-1
		Tape and Reel	4000	IRF7493TRPbF-1

**Absolute Maximum Ratings**

	Parameter	Max.	Units
$V_{DS}$	Drain-to-Source Voltage	80	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	
$I_D$ @ $T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} = 10V$	9.3	A
$I_D$ @ $T_A = 70^\circ C$	Continuous Drain Current, $V_{GS} = 10V$	7.4	
$I_{DM}$	Pulsed Drain Current ①	74	
$P_D$ @ $T_A = 25^\circ C$	Power Dissipation④	2.5	W
$P_D$ @ $T_A = 70^\circ C$	Power Dissipation ④	1.6	
	Linear Derating Factor	0.02	W/°C
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C

**Thermal Resistance**

	Parameter	Typ.	Max.	Units
$R_{\theta JL}$	Junction-to-Lead	—	20	°C/W
$R_{\theta JA}$	Junction-to-Ambient ④	—	50	

Notes ① through ⑤ are on page 9

**Static @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	80	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.074	—	mV/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 1\text{mA}$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	11.5	15	m $\Omega$	$V_{GS} = 10V, I_D = 5.6A$ ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	20	$\mu A$	$V_{DS} = 80V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 64V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-200		$V_{GS} = -20V$

**Dynamic @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

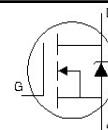
$g_{fs}$	Forward Transconductance	13	—	—	S	$V_{DS} = 15V, I_D = 5.6A$
$Q_g$	Total Gate Charge	—	35	53	ns	$I_D = 5.6A$
$Q_{gs}$	Gate-to-Source Charge	—	5.7	—		$V_{DS} = 40V$
$Q_{gd}$	Gate-to-Drain Charge	—	12	—		$V_{GS} = 10V$
$t_{d(on)}$	Turn-On Delay Time	—	8.3	—		$V_{DD} = 40V$ , ③
$t_r$	Rise Time	—	7.5	—	ns	$I_D = 5.6A$
$t_{d(off)}$	Turn-Off Delay Time	—	30	—		$R_G = 6.2\Omega$
$t_f$	Fall Time	—	12	—		$V_{GS} = 10V$
$C_{iss}$	Input Capacitance	—	1510	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	—	320	—		$V_{DS} = 25V$
$C_{rss}$	Reverse Transfer Capacitance	—	130	—		$f = 1.0\text{MHz}$
$C_{oss}$	Output Capacitance	—	1130	—		$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0\text{MHz}$
$C_{oss}$	Output Capacitance	—	210	—		$V_{GS} = 0V, V_{DS} = 64V, f = 1.0\text{MHz}$
$C_{rss\text{ eff.}}$	Effective Output Capacitance	—	320	—		$V_{GS} = 0V, V_{DS} = 0V \text{ to } 64V$ ⑤

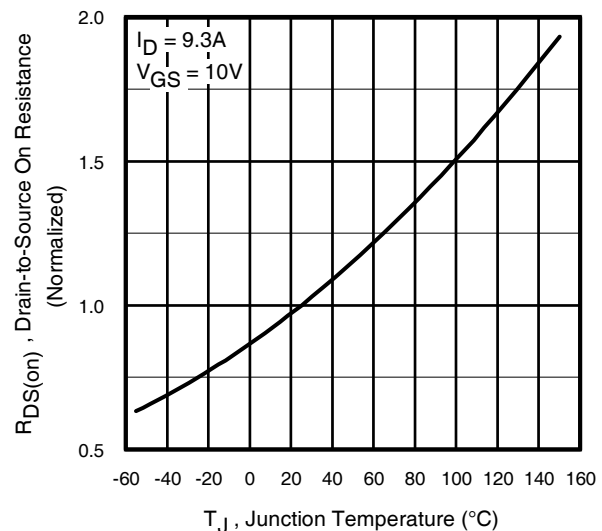
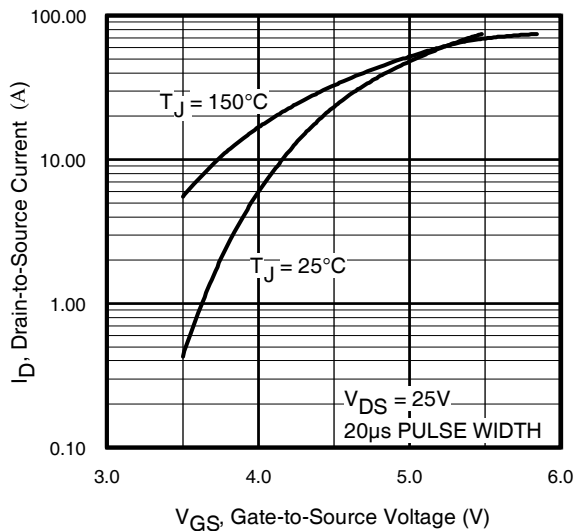
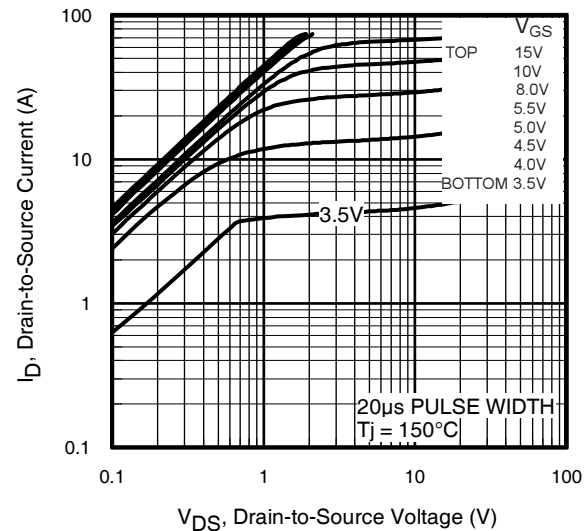
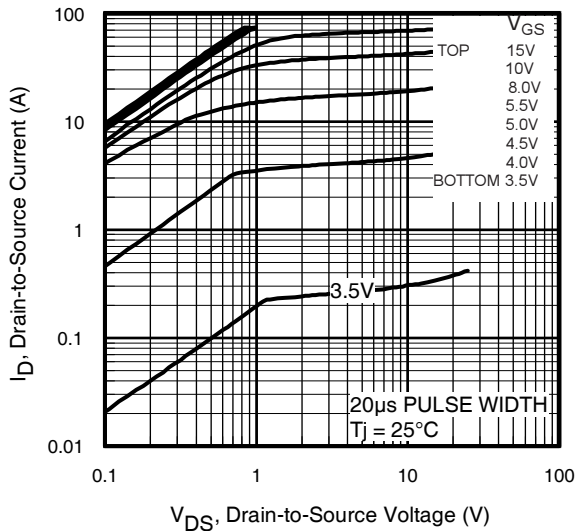
**Avalanche Characteristics**

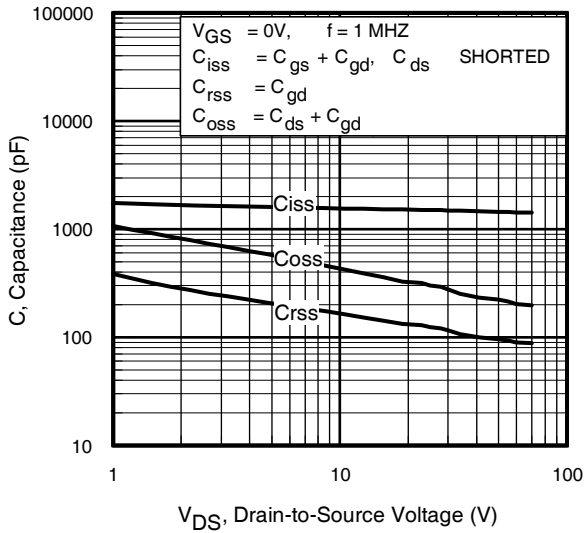
	Parameter	Typ.	Max.	Units
$E_{AS}$	Single Pulse Avalanche Energy ②	—	180	mJ
$I_{AR}$	Avalanche Current ①	—	5.6	A

**Diode Characteristics**

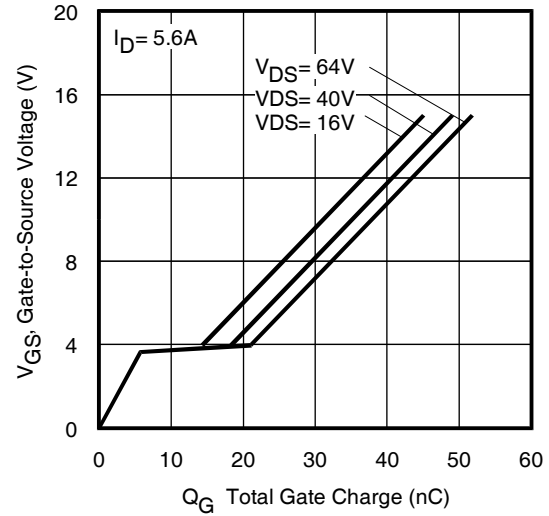
	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	9.3	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	74		
$V_{SD}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 5.6A, V_{GS} = 0V$ ③
$t_{rr}$	Reverse Recovery Time	—	37	56	ns	$T_J = 25^\circ\text{C}, I_F = 5.6A, V_{DD} = 15V$
$Q_{rr}$	Reverse Recovery Charge	—	52	78	nC	$di/dt = 100A/\mu s$ ③



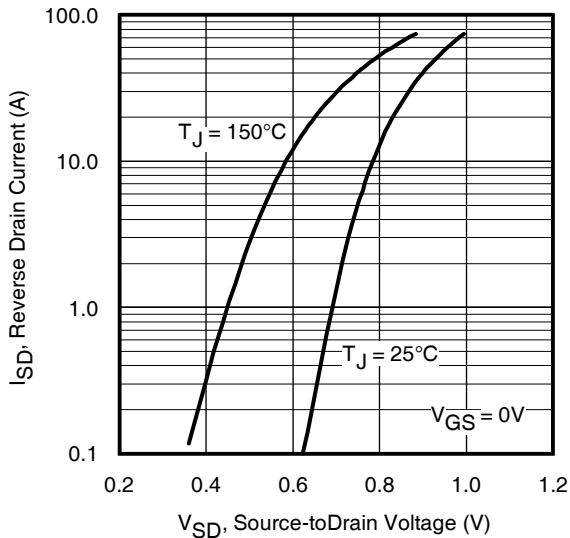




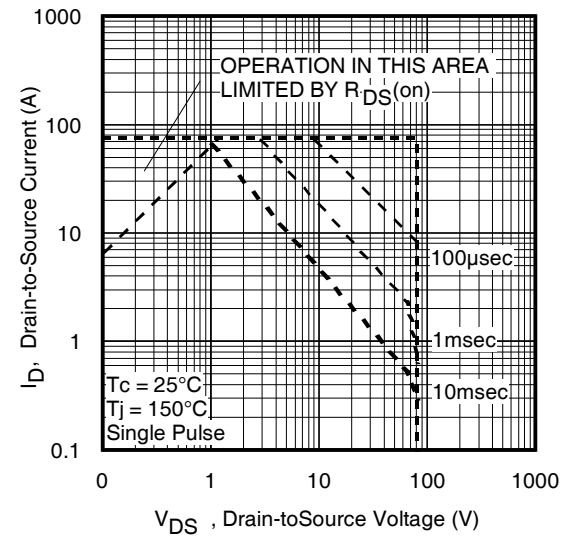
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



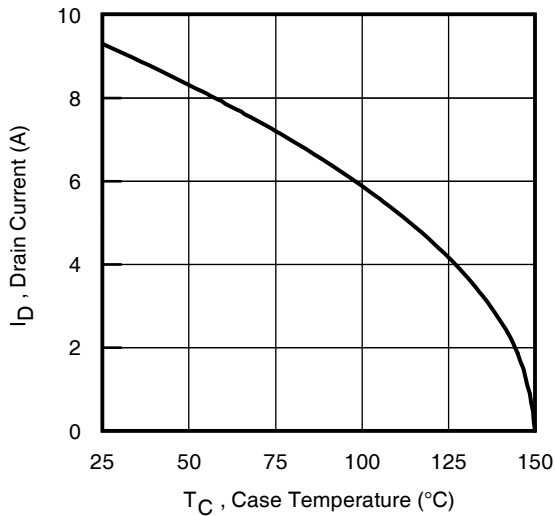
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



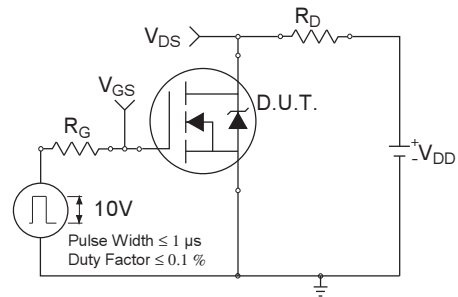
**Fig 7.** Typical Source-Drain Diode Forward Voltage



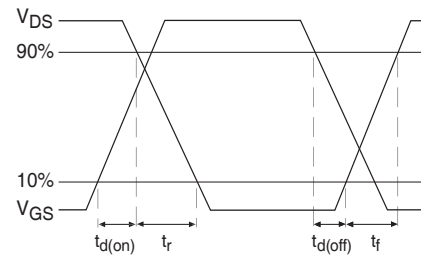
**Fig 8.** Maximum Safe Operating Area



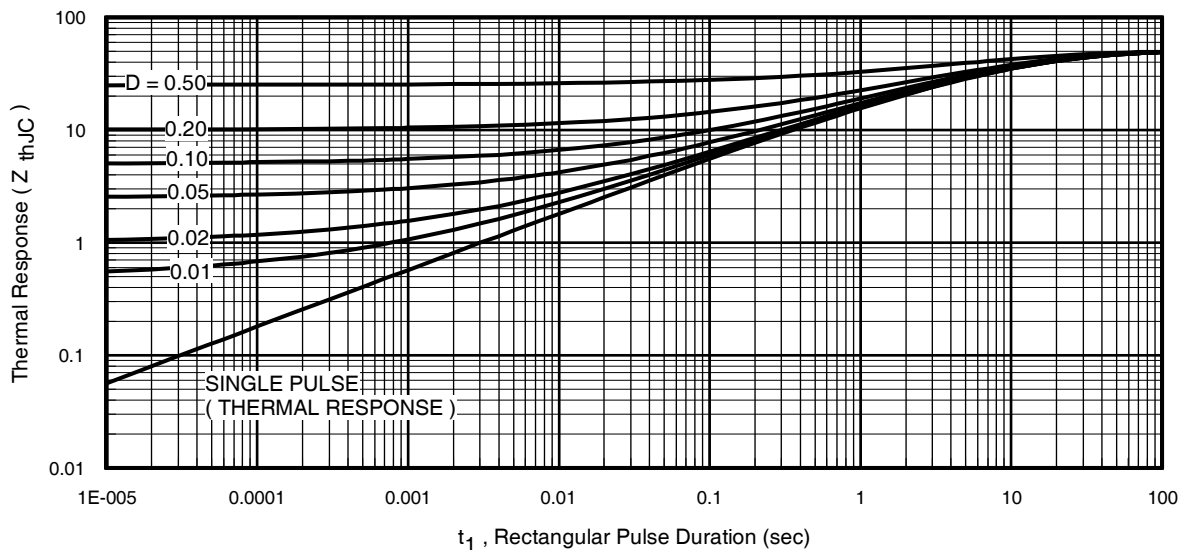
**Fig 9.** Maximum Drain Current Vs. Ambient Temperature



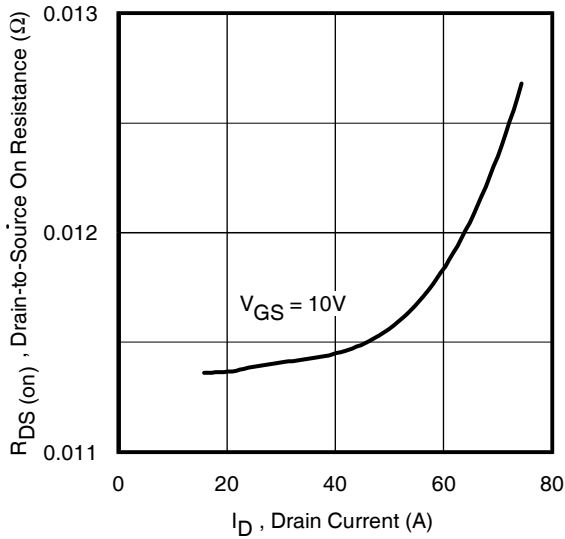
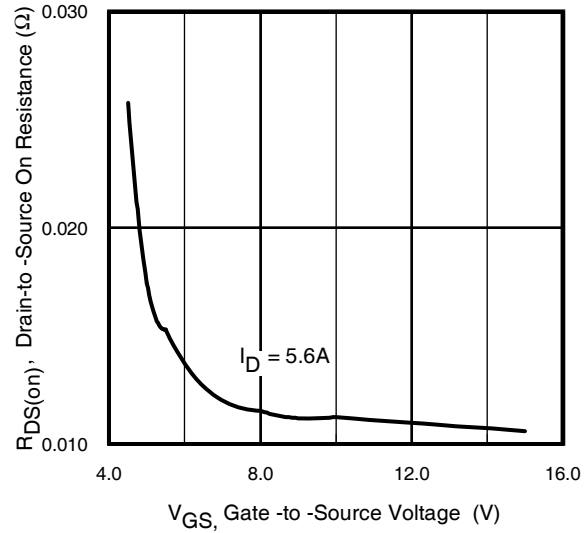
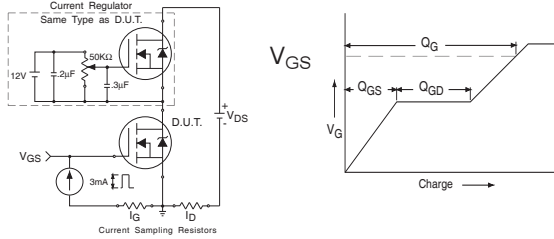
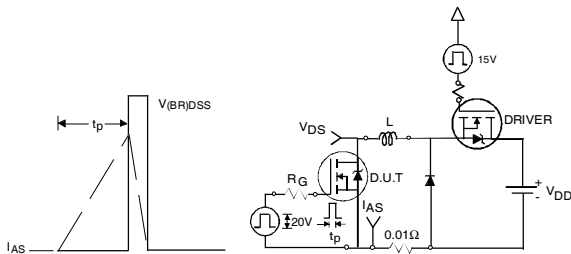
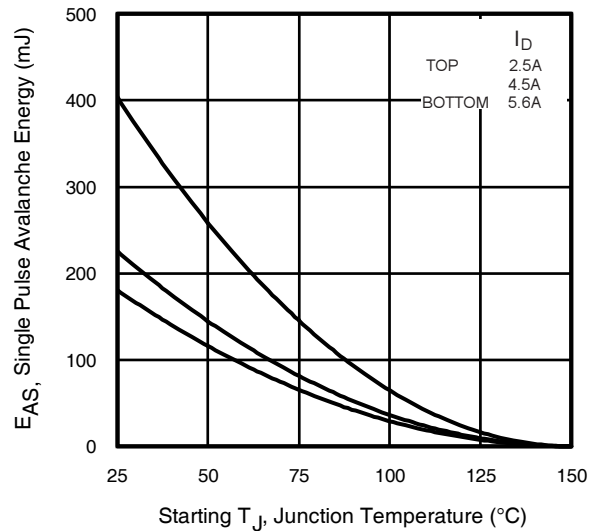
**Fig 10a.** Switching Time Test Circuit

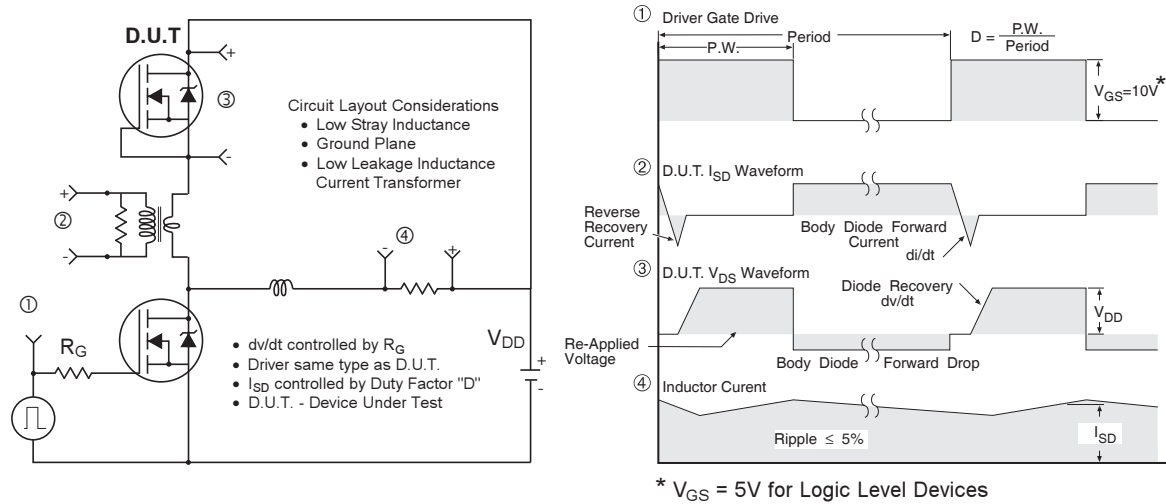


**Fig 10b.** Switching Time Waveforms

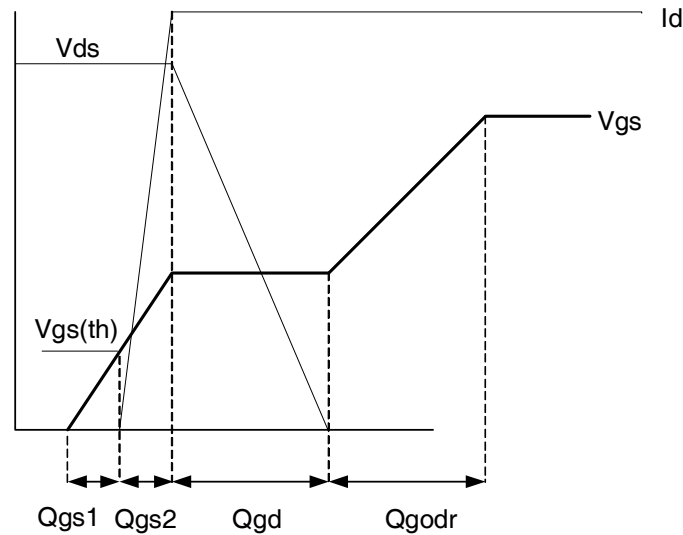


**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient


**Fig 12.** On-Resistance Vs. Drain Current

**Fig 13.** On-Resistance Vs. Gate Voltage

**Fig 14a&b.** Basic Gate Charge Test Circuit and Waveform

**Fig 15a&b.** Unclamped Inductive Test circuit and Waveforms

**Fig 15c.** Maximum Avalanche Energy Vs. Drain Current



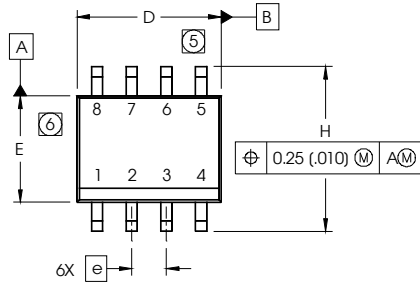
**Fig 16. Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs**



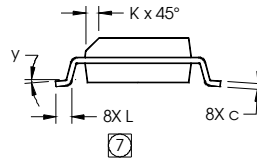
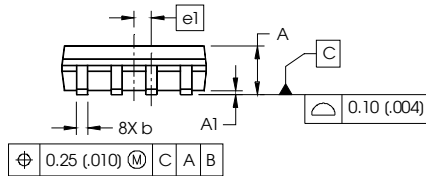
**Fig 17. Gate Charge Waveform**

## SO-8 Package Outline (MOSFET & Fetky)

Dimensions are shown in millimeters (inches)

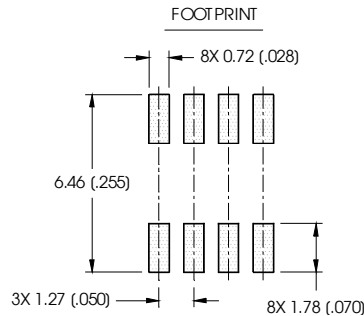


DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050 BASIC		1.27 BASIC	
e1	.025 BASIC		0.635 BASIC	
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°



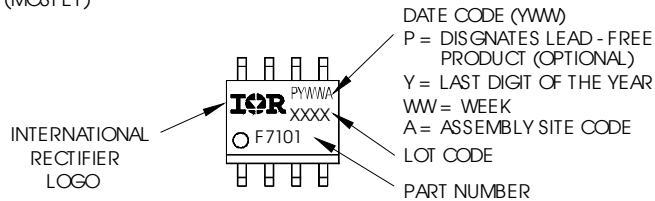
### NOTES:

1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: MILLIMETER
3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
5. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 (.006).
6. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.010).
7. DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.



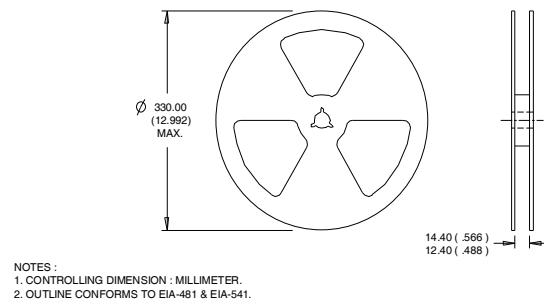
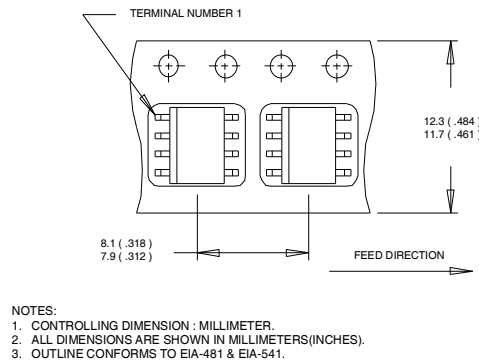
## SO-8 Part Marking Information

EXAMPLE: THIS IS AN IRF7101 (MOSFET)



Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>



**SO-8 Tape and Reel** (Dimensions are shown in millimeters (inches))


**Note:** For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 12\text{mH}$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 5.6\text{A}$ .
- ③ Pulse width  $\leq 300\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ④ When mounted on 1 inch square copper board
- ⑤  $C_{OSS}$  eff. is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

**Qualification information<sup>†</sup>**

Qualification level	Industrial (per JEDEC JESD47F <sup>††</sup> guidelines)	
Moisture Sensitivity Level	SO-8	MSL1 (per JEDEC J-STD-020D <sup>††</sup> )
RoHS compliant	Yes	

<sup>†</sup> Qualification standards can be found at International Rectifier's web site: <http://www.irf.com/product-info/reliability>

<sup>††</sup> Applicable version of JEDEC standard at the time of product release

International  
 Rectifier

**IR WORLD HEADQUARTERS:** 101 N. Sepulveda Blvd., El Segundo, California 90245, USA  
To contact International Rectifier, please visit <http://www.irf.com/whoto-call/>